

Silicon N-Channel Super-Junction Power MOSFET

General Description :

HMD20J60 the silicon N-channel Enhanced VDMOSFETS, is obtained by the self-aligned Superjunction Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency. The package form is TO-263, which accords with the RoHS standard.

Features :

- Fast Switching
- Low Gate Charge and R_{dson}
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

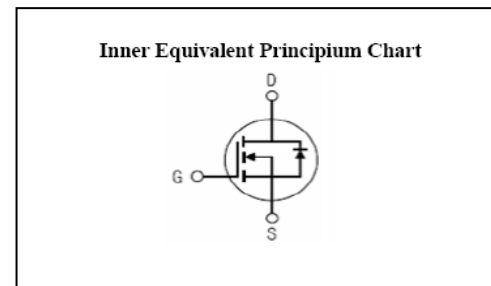
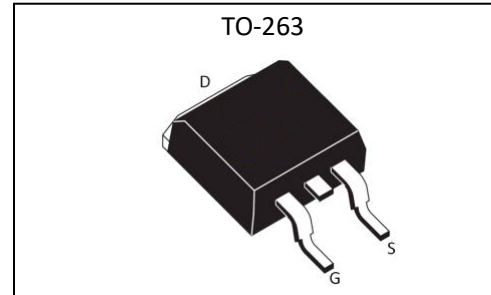
Applications :

- Switch Mode Power Supply(SMPS)
- Uninterruptible Power Supply(UPS)
- Power Factor Correction(PFC)

Absolute ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	600	V
I_D	Continuous Drain Current	20	A
	Continuous Drain Current $T_c = 100^\circ\text{C}$	15	A
I_{DM}^{a1}	Pulsed Drain Current	60	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	532	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	166	mJ
I_{AR}^{a1}	Avalanche Current	12	A
dv/dt^{a3}	Peak Diode Recovery dv/dt	15.0	V/ns
P_D	Power Dissipation	150	W
	Derating Factor above 25°C	1.2	W/ $^\circ\text{C}$
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150 , -55 to 150	$^\circ\text{C}$
T_L	MaximumTemperature for Soldering	300	$^\circ\text{C}$

$V_{DSS}(T_c=150^\circ\text{C})$	650	V
$V_{DSS}(T_c=25^\circ\text{C})$	600	V
I_D	20	A
$P_D(T_c=25^\circ\text{C})$	150	W
$R_{DS(ON)}$	0.12	Ω



Electrical Characteristics (Tc= 25°C unless otherwise specified) :

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	600	--	--	V
ΔBV _{DSS} /ΔT _J	Bvdss Temperature Coefficient	I _D =250uA, Reference 25°C	--	0.60	--	V/°C
I _{DSS}	Drain to Source Leakage Current	V _{DS} =600V, V _{GS} =0V, T _a =25°C	--	--	1	μA
		V _{DS} =480V, V _{GS} =0V, T _a =125°C	--	--	250	
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} = +30V	--	--	10	μA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} = -30V	--	--	-10	μA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} = 10V, I _D = 10A	--	0.12	0.15	Ω
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	2.0	3.0	4.0	V
Pulse width tp ≤ 380μs, δ ≤ 2%						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g _{fs}	Forward Transconductance	V _{DS} = 10V, I _D = 20A	--	18.8	--	S
C _{iss}	Input Capacitance	V _{GS} = 0V, V _{DS} = 25V f= 1.0MHz	--	1600	--	pF
C _{oss}	Output Capacitance		--	14	--	
C _{rss}	Reverse Transfer Capacitance		--	225	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	V _{DD} = 300V, I _D = 20A, V _{GS} = 10V, R _g = 25Ω	--	48	--	ns
t _r	Rise Time		--	108	--	
t _{d(OFF)}	Turn-Off Delay Time		--	176	--	
t _f	Fall Time		--	50	--	
Q _g	Total Gate Charge	I _D = 20A, V _{DD} = 480V V _{GS} = 0 to 10V	--	41	--	nC
Q _{gs}	Gate to Source Charge		--	8	--	
Q _{gd}	Gate to Drain ("Miller") Charge		--	15	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	20	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	60	A
V_{SD}	Diode Forward Voltage	$I_S=20A, V_{GS}=0V$	--	0.95	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=20A, T_J=25^\circ C$	--	440	--	ns
Q_{rr}	Reverse Recovery Charge	$di_F/dt=100A/us, V_{GS}=0V$	--	5	--	μC

Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	0.83	$^\circ C/W$
$R_{\theta JA}$	Junction-to-Ambient	62.5	$^\circ C/W$

^{a1} : Repetitive rating; pulse width limited by maximum junction temperature

^{a2} : $I_{AS}=6A, V_{DD}=50V, R_G=25\Omega$, Starting $T_J=25^\circ C$

^{a3} : $I_{SD}=20A, di/dt \leq 100A/us, V_{DD} \leq BV_{DS}$, Start $T_J=25^\circ C$

Test Circuit and Waveform

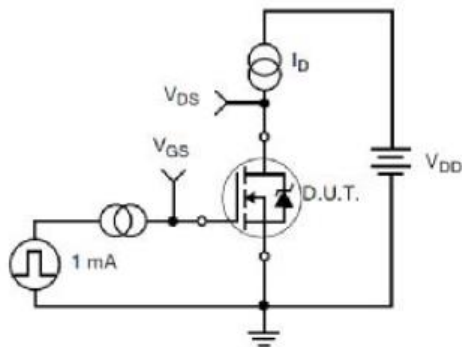


Figure 17. Gate Charge Test Circuit

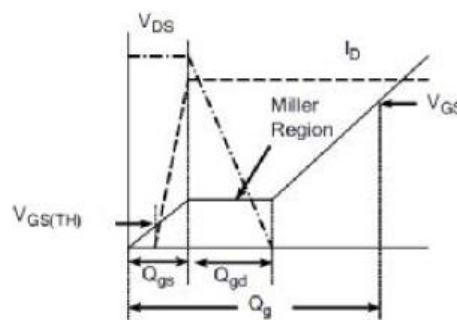


Figure 18. Gate Charge Waveform

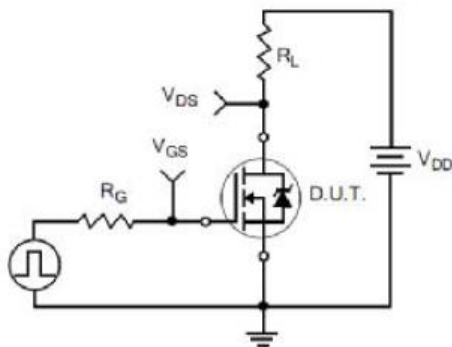


Figure 19. Resistive Switching Test Circuit

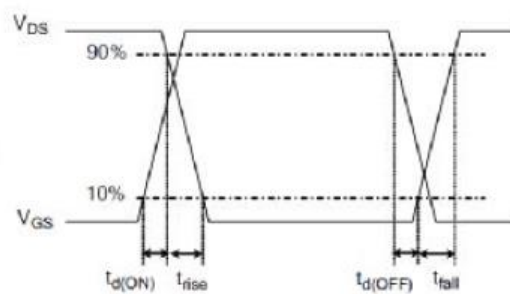


Figure 20. Resistive Switching Waveforms

Typical Characteristics

Figure 1. Output Characteristics

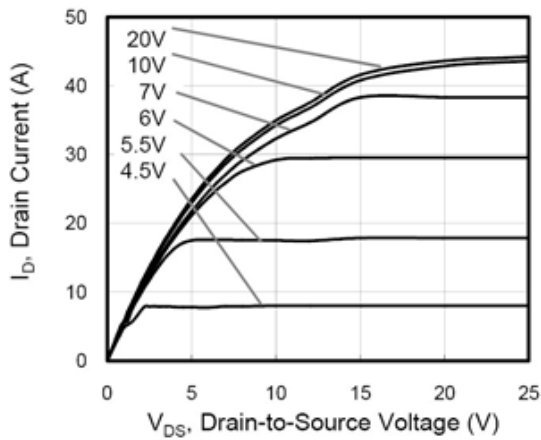


Figure 2. Transfer Characteristics

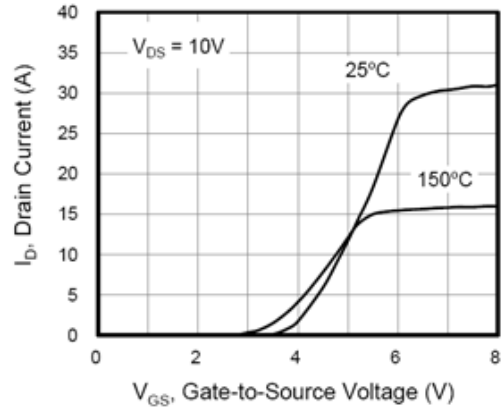


Figure 3. On-Resistance vs. Drain Current

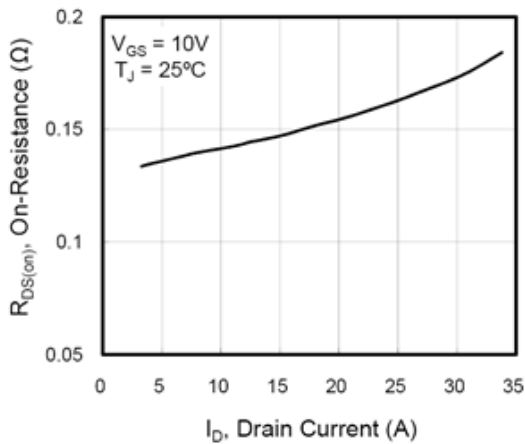


Figure 4. Capacitance

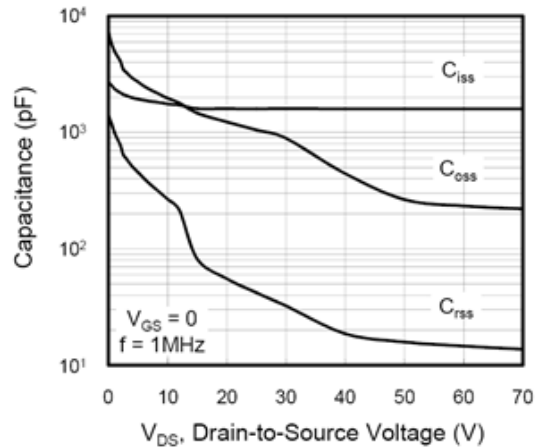


Figure 5. Gate Charge

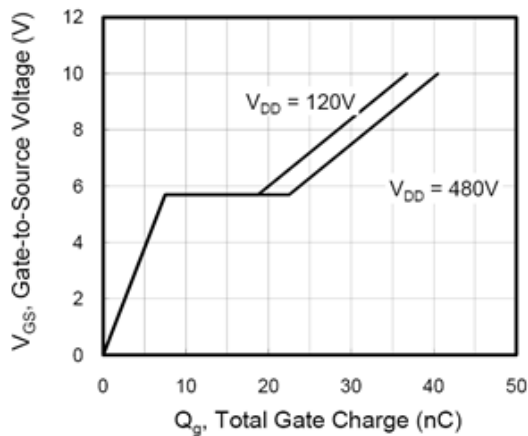


Figure 6. Body Diode Forward Voltage

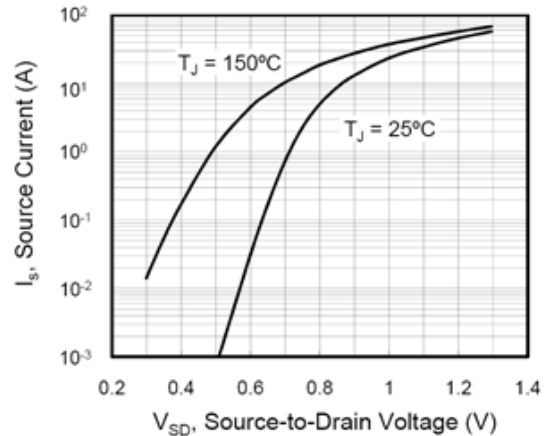


Figure 7. On-Resistance vs. Junction Temperature

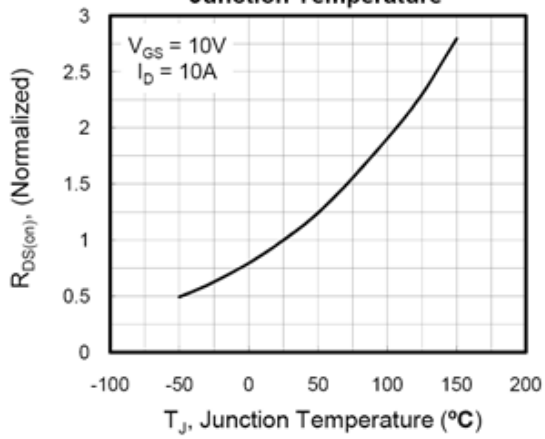


Figure 8. Threshold Voltage vs. Junction Temperature

